PCN Number:	20160928003	**PCN Date:**	Sept. 29, 2016
Title:	Qualification of HNT as Additional Assembly and Test Site for TPD2E1B06DRLR Device		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	Dec. 29, 2016	**Estimated Sample Availability:**	Date Provided at Sample request

Change Type:

☒	Assembly Site	☐	Design	☐	Wafer Bump Site
☐	Assembly Process	☐	Data Sheet	☐	Wafer Bump Material
☒	Assembly Materials	☐	Part number change	☐	Wafer Bump Process
☐	Mechanical Specification	☒	Test Site	☐	Wafer Fab Site
☒	Packing/Shipping/Labeling	☐	Test Process	☐	Wafer Fab Materials
				☐	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments Incorporated is announcing the qualification of HNT as Additional Assembly and Test Site for TPD2E1B06DRLR Device. Current assembly sites and Material differences are as follows.

Assembly Site	Assembly Site Origin	Assembly Country Code	Assembly Site City
JCET Co. Ltd	JCE	CHN	Jiangyin
Hana Semiconductor	**HNT**	**THA**	**Ayutthaya**

Material Differences:

	JCET	HNT
Mount Compound	120402001600	400173
Mold compound	111020003809	450214

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Reason for Change:

Continuity of supply.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Assembly Site		
JCET Co. Ltd	Assembly Site Origin (22L)	ASO: JCE
Hana Semiconductor	Assembly Site Origin (22L)	ASO: HNT

Sample product shipping label (not actual product label)

ASSEMBLY SITE CODES: JCET = F , HNT = H

Product Affected:

TPD2E1B06DRLR

Qualification Report

New Product Qual: TPD4E1B06DRLR (CFAB VDIODE / JCET DRL)

Approved05/21/2014

Product Attributes

Attributes	Qual Device: TPD4E1B06DRLR	QBS Product: TPD2E1B06DRLR	QBS Process: TPD4E1U06DCKR	QBS Pkg: TMP102AIDRL	QBS Pkg: TPD2E1B06DRLR
Assembly Site	JCET	JCET	NFME	JCET	JCET
Package Family	-	-	SC70-6A (6F2)	SOT	-
Flammability Rating	UL 94 V-0	UL 94 V-0	-	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	CFAB	CFAB	CFAB	DM5	CFAB
Wafer Fab Process	VDIODE ULC (DIODE-ST14)	VDIODE ULC (DIODE-ST14)	VD-ULC	33HPA07	VDIODE ULC (DIODE-ST14)

- QBS: Qual By Similarity
- Qual Device TPD4E1B06DRLR is qualified at LEVEL1-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TPD4E1B06DRLR	QBS Product: TPD2E1B06DRLR	QBS Process: TPD4E1U06DCKR	QBS Pkg: TMP102AIDRL	QBS Pkg: TPD2E1B06DRLR
HAST	Biased HAST 130C/85%RH	96 Hours	-	-	-	3/231/0	-
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	1/80/0	3/231/0	3/231/0	1/80/0
TC	Temperature Cycle -65/150C	500 Cycles	-	1/80/0	3/231/0	3/228/0	1/80/0
HTSL	High Temp Storage Bake 170C	420 Hours	-	1/80/0	3/231/0	3/231/0	1/80/0
LI	Lead Fatigue to Destruction	Leads	-	-	-	3/66/0	-
HTOL	Life Test, 150C	300 Hours	-	1/78/0	3/231/0	3/229/0	1/78/0
WBP	Bond Pull	Wires	-	1/76/0	-	-	1/76/0
SD	Solderability	8 Hours Steam Age	-	-	-	3/66/0	-
PD	Physical Dimensions	--	-	-	-	3/15/0	-
HBM	ESD - HBM	1000 V	1/3/0	1/3/0	3/9/0	-	1/3/0
CDM	ESD - CDM	250 V	1/3/0	1/3/0	3/9/0	1/3/0	1/3/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
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